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Kleinfelder, S.; Bieser, F.; Yandong Chen; Gareus, R.; Matis, H.S.; Oldenburg, Ritter, H.G.; Wieman, H.H.; Yamamoto, E.;
Nuclear Science, IEEE Transactions on
Volume 51, Issue 5, Part 1, Oct. 2004 Page(s):2328 - 2336
Digital Object Identifier 10.1109/TNS.2004.836150
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